TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74VCX16835FT

Low-Voltage 18-Bit Universal Bus Driver with 3.6-V Tolerant Inputs and Outputs

The TC74VCX16835FT is a high-performance CMOS 18-bit universal bus driver. Designed for use in 1.8-V, 2.5-V or 3.3-V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

It is also designed with overvoltage tolerant inputs and outputs up to 3.6 V.

Data flow from A to Y is controlled by the output-enable  $(\overline{\rm OE})$  input.

The device operates in the transparent mode when the latch-enable (LE) input is high. When LE is low, the A data is latched if the clock (CK) input is held at a high or low logic level. If LE is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CK.

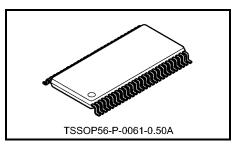
When  $\overline{OE}$  is high, the outputs are in the high-impedance state. All inputs are equipped with protection circuits against static discharge.

### Features

- Low-voltage operation: V<sub>CC</sub> = 1.8 to 3.6 V
  - High-speed operation:  $t_{pd} = 3.3 \text{ ns} (\text{max}) (V_{CC} = 3.0 \text{ to } 3.6 \text{ V})$ 
    - :  $t_{pd}$  = 4.2 ns (max) (V<sub>CC</sub> = 2.3 to 2.7 V)
    - :  $t_{pd} = 8.4 \text{ ns} (\text{max}) (\text{V}_{CC} = 1.8 \text{ V})$
- Output current:  $I_{OH}/I_{OL} = \pm 24 \text{ mA} (min) (V_{CC} = 3.0 \text{ V})$ 
  - :  $I_{OH}/I_{OL} = \pm 18 \text{ mA} \text{ (min)} (V_{CC} = 2.3 \text{ V})$
  - :  $I_{OH}/I_{OL} = \pm 6 \text{ mA} \text{ (min)} (V_{CC} = 1.8 \text{ V})$
- Latch-up performance: -300 mA
- ESD performance: Machine model  $\geq \pm 200 \text{ V}$

Human body model  $\geq \pm 2000~V$ 

- Package: TSSOP
- 3.6-V tolerant function and power-down protection is provided on all inputs and outputs



Weight: 0.25 g (typ.)

## <u>TOSHIBA</u>

### Pin Assignment (top view)

	1		1	
NC	1	0	56	GND
NC	2		55	NC
Y1	3		54	A1
GND	4		53	GND
Y2	5		52	A2
Y3	6		51	A3
Vcc	7		50	Vcc
Y4	8		49	A4
Y5	9		48	A5
Y6	10		47	A6
GND	11		46	GND
Y7	12		45	A7
Y8	13		44	A8
Y9	14		43	A9
Y10	15		42	A10
Y11	16		41	A11
Y12	17		40	A12
GND	18		39	GND
Y13	19		38	A13
Y14	20		37	A14
Y15	21		36	A15
V <sub>CC</sub>	22		35	V <sub>CC</sub>
Y16	23		34	A16
Y17	24		33	A17
GND	25		32	GND
Y18	26		31	A18
ŌE	27		30	СК
LE	28		29	GND

### IEC Logic Symbol

СК ——	27 N 30 28	EN1 > 2C3 C3 G2				
Y1 —	3	1 🗸	1	3D	54	A1
Y2 —	5				52	A2
Y3 —	6				51	A3
Y4 —	8				49	A4
Y5 —	9				48	A5
Y6 —	10				47	- A6
Y7 —	12				45	· A7
Y8 ——	13				44	- A8
Y9 ——	14				43	- A9
Y10	15				42	· A9
Y11	16				41	
	17				40	• A1
Y12 —	19				38	• A1
Y13 —	20				37	A1
Y14 —	21				36	A1
Y15 —	23				34	A1
Y16 ——	24				33	· A1
Y17 —						· A1
Y18 —	26				31	A1

### Truth Table

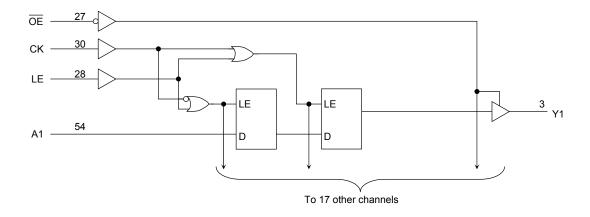
	Inp	outs		Outputs
ŌĒ	LE	СК	А	Y
Н	Х	Х	Х	Z
L	Н	Х	L	L
L	Н	Х	Н	н
L	L		L	L
L	L		Н	н
		н	х	Y0
L	L	п	^	(Note)
			х	Y0
L	L	L	^	(Note)

X: Don't care

Z: High impedance

Note: Output level before the indicated steady-state input conditions were established, provided that CK was high or low before LE went low.

### System Diagram



### **Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit
Power supply voltage	V <sub>CC</sub>	-0.5 to 4.6	V
DC input voltage	V <sub>IN</sub>	-0.5 to 4.6	V
		-0.5 to 4.6 (Note 2)	
DC output voltage	V <sub>OUT</sub>	$-0.5$ to $V_{CC} + 0.5$	V
		(Note 3)	
Input diode current	I <sub>IK</sub>	-50	mA
Output diode current	IOK	±50 (Note 4)	mA
DC output current	IOUT	±50	mA
Power dissipation	PD	400	mW
DC $V_{CC}$ /ground current per supply pin	I <sub>CC</sub> /I <sub>GND</sub>	±100	mA
Storage temperature	T <sub>stg</sub>	-65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: OFF state

Note 3: High or low state. IOUT absolute maximum rating must be observed.

Note 4:  $V_{OUT} < GND, V_{OUT} > V_{CC}$ 

#### **Operating Ranges (Note 1)**

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V <sub>CC</sub>	1.8 to 3.6	V	
Tower supply voltage	VCC	1.2 to 3.6 (Note 2)	v	
Input voltage	V <sub>IN</sub>	-0.3 to 3.6	V	
Output voltage	Vout	0 to 3.6 (Note 3)	V	
Output voltage	V001	0 to V <sub>CC</sub> (Note 4)		
		±24 (Note 5)		
Output current	IOH/IOL	±18 (Note 6)	mA	
		±6 (Note 7)		
Operating temperature	T <sub>opr</sub>	-40 to 85	°C	
Input rise and fall time	dt/dv	0 to 10 (Note 8)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: OFF state

Note 4: High or low state

Note 5:  $V_{CC} = 3.0$  to 3.6 V

Note 6:  $V_{CC} = 2.3$  to 2.7 V

Note 7:  $V_{CC} = 1.8 V$ 

Note 8:  $V_{IN} = 0.8$  to 2.0 V,  $V_{CC} = 3.0$  V

### **Electrical Characteristics**

### DC Characteristics (Ta = -40 to 85°C, 2.7 V < V<sub>CC</sub> $\leq$ 3.6 V)

Character	istics	Symbol	Test	Condition		Min	Max	Unit
		- ,					max	Öim
Input voltage	H-level	VIH		—	2.7 to 3.6	2.0	_	v
input voltage	L-level	VIL		_	2.7 to 3.6	_	0.8	v
				$I_{OH} = -100 \ \mu A$	2.7 to 3.6	V <sub>CC</sub> - 0.2	_	
H-level Output voltage	H-level	V <sub>OH</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -12 \text{ mA}$	2.7	2.2	_	
				$I_{OH} = -18 \text{ mA}$	3.0	2.4		
				I <sub>OH</sub> = -24 mA	3.0	2.2		V
		level V <sub>OL</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 100 \ \mu A$	2.7 to 3.6		0.2	
				$I_{OL} = 12 \text{ mA}$	2.7	_	0.4	
	L-level			$I_{OL} = 18 \text{ mA}$	3.0	_	0.4	
				$I_{OL} = 24 \text{ mA}$	3.0	_	0.55	
Input leakage curre	ent	lin	$V_{IN} = 0$ to 3.6 V		2.7 to 3.6		±5.0	μA
			$V_{IN} = V_{IH} \text{ or } V_{IL}$		0.7 4- 0.0		140.0	^
3-state output OFF	state current	I <sub>OZ</sub>	V <sub>OUT</sub> = 0 to 3.6 V		2.7 to 3.6	—	±10.0	μA
Power-off leakage	current	IOFF	$V_{IN}$ , $V_{OUT} = 0$ to 3.6	V	0		10.0	μA
	ourropt	laa	$V_{IN} = V_{CC}$ or GND		2.7 to 3.6	_	20.0	
	Quiescent supply current	Icc	$V_{CC} \leq (V_{IN}, V_{OUT}) \leq 3.6 \text{ V}$		2.7 to 3.6		±20.0	μA
Increase in ICC pe	r input	Δlcc	$V_{IH} = V_{CC} - 0.6 V$		2.7 to 3.6		750	

### DC Characteristics (Ta = -40 to 85°C, 2.3 V $\leq$ V<sub>CC</sub> $\leq$ 2.7 V)

Characteris	stics	Symbol	Test C	ondition	V <sub>CC</sub> (V)	Min	Max	Unit
Input voltage	H-level	VIH	-	_	2.3 to 2.7	1.6	_	V
Input voltage	L-level	V <sub>IL</sub>	-		2.3 to 2.7	_	0.7	v
H-level Output voltage				I <sub>OH</sub> = -100 μA	2.3 to 2.7	V <sub>CC</sub> - 0.2	_	
	H-level	Voh	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -6 \text{ mA}$	2.3	2.0	_	
				$I_{OH} = -12 \text{ mA}$	2.3	1.8	_	V
				$I_{OH} = -18 \text{ mA}$	2.3	1.7	_	
				$I_{OL} = 100 \ \mu A$	2.3 to 2.7	_	0.2	
	L-level	V <sub>OL</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 12 \text{ mA}$	2.3	_	0.4	
				$I_{OL} = 18 \text{ mA}$	2.3	_	0.6	
Input leakage currer	nt	I <sub>IN</sub>	$V_{IN} = 0$ to 3.6 V		2.3 to 2.7	_	±5.0	μA
3-state output OFF	state current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \text{ to } 3.6 \text{ V}$		2.3 to 2.7	_	±10.0	μΑ
Power-off leakage c	urrent	IOFF	V <sub>IN</sub> , V <sub>OUT</sub> = 0 to 3.6 V			_	10.0	μA
	umo et		$V_{IN} = V_{CC}$ or GND		2.3 to 2.7	_	20.0	
Quiescent supply cu	lirent	Icc	$V_{CC} \leq (V_{IN}, V_{OUT}) \leq 3.$	$V_{CC} \leq (V_{IN}, V_{OUT}) \leq 3.6 \text{ V}$		_	±20.0	μA

### DC Characteristics (Ta = –40 to 85°C, 1.8 V $\leq$ V<sub>CC</sub> < 2.3 V)

Characteri	stics	Symbol	Test Co	ondition		Min	Max	Unit
		-			V <sub>CC</sub> (V)			
Input voltage	H-level	VIH	-	_	1.8 to 2.3	$0.7 \times V_{CC}$	_	V
L-level	L-level	V <sub>IL</sub>	_	_	1.8 to 2.3	_	$0.2 \times V_{CC}$	v
H-level	H-level	Vон	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OH</sub> = -100 μA	1.8	V <sub>CC</sub> - 0.2	_	
				I <sub>OH</sub> = -6 mA	1.8	1.4	_	V
	L-level	V <sub>OL</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OL</sub> = 100 μA	1.8	_	0.2	
	L-IEVEI			$I_{OL} = 6 \text{ mA}$	1.8	_	0.3	
Input leakage curre	nt	I <sub>IN</sub>	$V_{IN} = 0$ to 3.6 V	·	1.8	_	±5.0	μA
3-state output OFF state current		I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \text{ to } 3.6 \text{ V}$			_	±10.0	μA
Power-off leakage of	current	I <sub>OFF</sub>	$V_{IN}$ , $V_{OUT} = 0$ to 3.6 V	V <sub>IN</sub> , V <sub>OUT</sub> = 0 to 3.6 V		_	10.0	μA
Quiescent supply c	Quieseent europhy europh		$V_{IN} = V_{CC} \text{ or } GND$		1.8	_	20.0	μA
Quicacent supply c		Icc	$V_{CC} \leq (V_{IN}, V_{OUT}) \leq 3.6 \text{ V}$		1.8		±20.0	μA

### AC Characteristics (Ta = -40 to 85°C, input: $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500 \Omega$ )

Characteristics	Symbol	Test Condition		Min	Max	Unit
Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	IVIIII	IVIAX	Offic
		Figure 1, Figure 3	1.8	100	_	MHz
Maximum clock frequency	f <sub>max</sub>		$\textbf{2.5}\pm\textbf{0.2}$	200	_	
			$\textbf{3.3}\pm\textbf{0.3}$	250		
			1.8	1.5	8.4	
Propagation delay time	t <sub>pLH</sub>	Figure 1, Figure 2	$\textbf{2.5}\pm\textbf{0.2}$	0.8	4.2	ns
(An-Yn)	tpHL		$\textbf{3.3}\pm\textbf{0.3}$	0.6	3.3	
Design and the state of the state			1.8	2.0	9.2	
Propagation delay time	t <sub>pLH</sub>	Figure 1, Figure 3	$\textbf{2.5}\pm\textbf{0.2}$	1.5	5.2	ns
(CK-Yn)	tpHL		$\textbf{3.3}\pm\textbf{0.3}$	1.4	4.2	
Propagation delay time (LE-Yn)			1.8	1.5	9.8	
	t <sub>pLH</sub>	Figure 1, Figure 4	$\textbf{2.5}\pm\textbf{0.2}$	0.8	4.9	ns
	tpHL		$\textbf{3.3}\pm\textbf{0.3}$	0.6	3.8	
		Figure 1, Figure 5	1.8	1.5	9.8	ns
Output enable time	t <sub>pZL</sub>		$\textbf{2.5}\pm\textbf{0.2}$	0.8	4.9	
	<sup>t</sup> pZH		$\textbf{3.3}\pm\textbf{0.3}$	0.6	3.8	
		Figure 1, Figure 5	1.8	1.5	7.6	ns
Output disable time	t <sub>pLZ</sub>		$\textbf{2.5}\pm\textbf{0.2}$	0.8	4.5	
	<sup>t</sup> pHZ		$\textbf{3.3}\pm\textbf{0.3}$	0.6	3.9	
			1.8	4.0		
Minimum pulse width	tw (H)	Figure 1, Figure 3, Figure 4	$\textbf{2.5}\pm\textbf{0.2}$	1.5		ns
	t <sub>W (L)</sub>		$\textbf{3.3}\pm\textbf{0.3}$	1.5	_	
Minimum octum time			1.8	2.5	—	
Minimum setup time (An-CK, An-LE)	ts	Figure 1, Figure 3, Figure 4	$\textbf{2.5}\pm\textbf{0.2}$	1.5	_	ns
(AII-CK, AII-LE)			$\textbf{3.3}\pm\textbf{0.3}$	1.5		
Minimum hald finan			1.8	1.0	_	
Minimum hold time (An-CK, An-LE)	t <sub>h</sub>	Figure 1, Figure 3, Figure 4	$2.5\pm0.2$	0.7		ns
(AII-OK, AII-LE)			$\textbf{3.3}\pm\textbf{0.3}$	0.7		
			1.8	_	0.5	
Output to output skew	t <sub>osLH</sub>	(Note)	$\textbf{2.5}\pm\textbf{0.2}$	_	0.5	ns
	tosHL		$\textbf{3.3}\pm\textbf{0.3}$	_	0.5	

Note: Parameter guaranteed by design.

 $(t_{osLH} = |t_{pLHm} - t_{pLHn}|, t_{osHL} = |t_{pHLm} - t_{pHLn}|)$ 

### AC Characteristics (Ta = 0 to 85°C, input: $t_r = t_f = 2.0$ ns, $C_L = 0$ pF, $R_L = 500 \Omega$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit
Propagation delay time (An-Yn)	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 2 (Note)	3.3 ± 0.15	0.9	2.0	ns
Propagation delay time (CK-Yn)	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 3 (Note)	3.3 ± 0.15	1.5	2.9	ns
Propagation delay time (LE-Yn)	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 4 (Note)	3.3 ± 0.15	0.7	2.6	ns
Output enable time	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 5 (Note)	$\textbf{3.3}\pm\textbf{0.15}$	0.7	2.6	ns
Output disable time	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 5 (Note)	$\textbf{3.3} \pm \textbf{0.15}$	0.7	2.7	ns
Minimum setup time (An-CK, An-LE)	ts	Figure 1, Figure 3, Figure 4 (Note)	$\textbf{3.3}\pm\textbf{0.15}$	1.5		ns
Minimum hold time (An-CK, An-LE)	t <sub>h</sub>	Figure 1, Figure 3, Figure 4 (Note)	3.3 ± 0.15	0.7	_	ns

Note: TOSHIBA SPICE simulation data.

### AC Characteristics (Ta = 0 to 85°C, input: $t_r = t_f = 2.0 \text{ ns}$ , $C_L = 50 \text{ pF}$ , $R_L = 500 \Omega$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit
Propagation delay time	t <sub>pLH</sub>	Figure 1, Figure 2	3.3 ± 0.15	1.0	3.6	ns
(An-Yn)	t <sub>pHL</sub>		0.0 ± 0.10	1.0	0.0	110
Propagation delay time	t <sub>pLH</sub>	Figure 1 Figure 2	3.3 ± 0.15	1.7	4.5	20
(CK-Yn)	t <sub>pHL</sub>	Figure 1, Figure 3	5.5 ± 0.15	1.7	4.5	ns
Propagation delay time	t <sub>pLH</sub>		3.3 ± 0.15	1.0	4.1	
(LE-Yn)	t <sub>pHL</sub>	Figure 1, Figure 4	5.5 ± 0.15	1.0	4.1	ns
Output anable time	t <sub>pZL</sub>	Figure 1, Figure 5	3.3 ± 0.15	1.0	4.1	20
Output enable time	t <sub>pZH</sub>		5.5 ± 0.15	1.0	4.1	ns
Output disable time	t <sub>pLZ</sub>		3.3 ± 0.15	1.0	4.2	20
Output disable time	t <sub>pHZ</sub>	Figure 1, Figure 5	5.5 ± 0.15	1.0	4.2	ns
Minimum setup time		Figure 1 Figure 2 Figure 4	2.2 + 0.45	4 5		
(An-CK, An- LE)	ts	Figure 1, Figure 3, Figure 4	3.3 ± 0.15	1.5	_	ns
Minimum hold time			0.0 1 0.45	0.7		
(An-CK, An-LE)	t <sub>h</sub>	Figure 1, Figure 3, Figure 4	$3.3\pm0.15$	0.7	—	ns

### **Dynamic Switching Characteristics**

 $(Ta = 25^{\circ}C, input: t_r = t_f = 2.0 \text{ ns}, C_L = 30 \text{ pF}, R_L = 500 \Omega)$ 

Characteristics	Symbol	Test Condition			Тур.	Unit
	Cymbol			$V_{CC}\left(V\right)$	199.	Onit
Quiet output maximum dynamic V <sub>OL</sub>		$V_{IH} = 1.8 V, V_{IL} = 0 V$ (	(Note)	1.8	0.35	
	V <sub>OLP</sub>	$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (	(Note)	2.5	0.7	V
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (	(Note)	3.3	0.9	
	V <sub>OLV</sub>	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (	(Note)	1.8	-0.35	v
Quiet output minimum dynamic V <sub>OI</sub>		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (	(Note)	2.5	-0.7	
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (	(Note)	3.3	-0.9	
		$V_{IH} = 1.8 V, V_{IL} = 0 V$ (	(Note)	1.8	1.3	v
Quiet output minimum dynamic V <sub>OH</sub>	V <sub>OHV</sub>	$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (	(Note)	2.5	1.7	
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (	(Note)	3.3	2.0	

Note: Parameter guaranteed by design.

#### **Capacitive Characteristics (Ta = 25°C)**

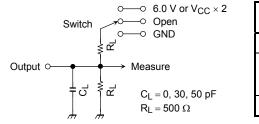
Characteristics	Symbol	Test Condition			Tun	Unit
Characteristics				V <sub>CC</sub> (V)	Тур.	Unit
Input capacitance	C <sub>IN</sub>	_		1.8, 2.5, 3.3	6	pF
Output capacitance	C <sub>OUT</sub>			1.8, 2.5, 3.3	7	pF
Power dissipation capacitance	C <sub>PD</sub>	$f_{IN} = 10 \text{ MHz} \tag{N}$	lote)	1.8, 2.5, 3.3	20	pF

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/18$  (per bit)

### AC Test Circuit



Parameter	Switch		
t <sub>pLH</sub> , t <sub>pHL</sub>	Open		
t <sub>pLZ</sub> , t <sub>pZL</sub>	$ \begin{array}{ll} 6.0 \ V & @V_{CC} = 3.3 \pm 0.3 \ V \\ V_{CC} \times 2 & @V_{CC} = 2.5 \pm 0.2 \ V \\ @V_{CC} = 1.8 \ V \end{array} $		
t <sub>pHZ</sub> , t <sub>pZH</sub>	GND		

Figure 1

### **AC Waveform**

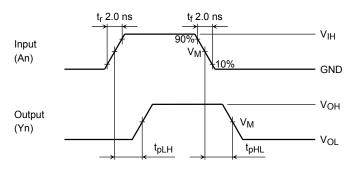
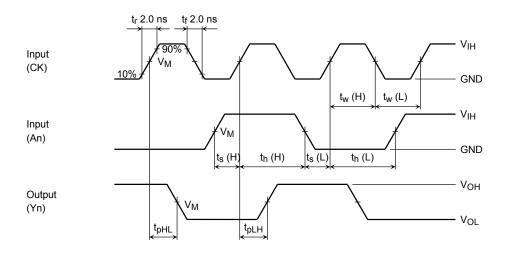


Figure 2 t<sub>pLH</sub>, t<sub>pHL</sub>



 $\label{eq:Figure 3} \quad t_{pLH}, \, t_{pHL}, \, t_w, \, t_s, \, t_h$ 

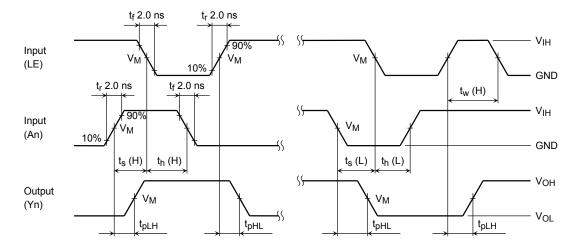
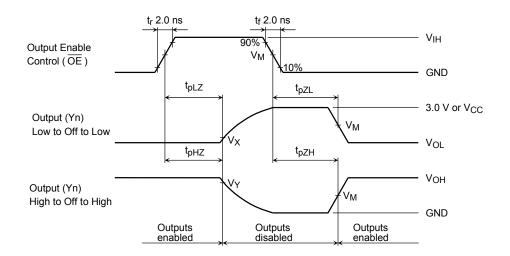
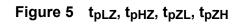


Figure 4 t<sub>pLH</sub>, t<sub>pHL</sub>, t<sub>w</sub>, t<sub>s</sub>, t<sub>h</sub>





Symbol	V <sub>CC</sub>						
Symbol	$3.3\pm0.3~V$	$2.5\pm0.2\;V$	1.8 V				
VIH	2.7 V	V <sub>CC</sub>	V <sub>CC</sub>				
VM	1.5 V	V <sub>CC</sub> /2	V <sub>CC</sub> /2				
VX	$V_{OL}$ + 0.3 V	V <sub>OL</sub> + 0.15 V	$V_{OL}$ + 0.15 V				
Vy	V <sub>OH</sub> – 0.3 V	V <sub>OH</sub> – 0.15 V	V <sub>OH</sub> – 0.15 V				

### **IBIS Characteristics (typ.)**

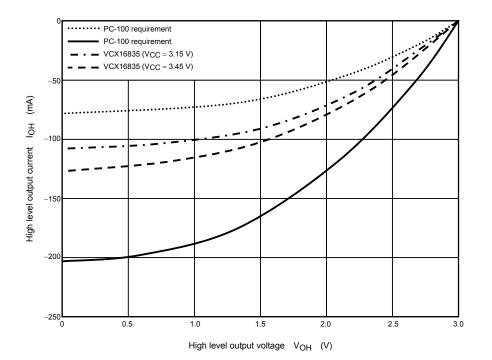


Figure 6 I/V Characteristics-Pullup

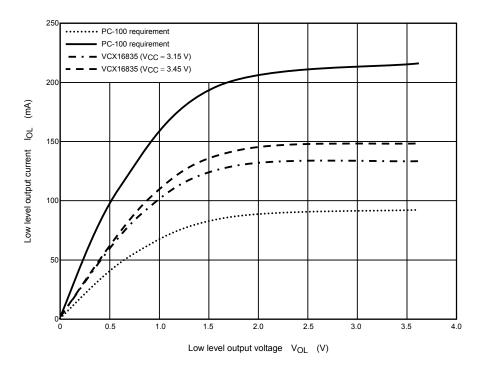
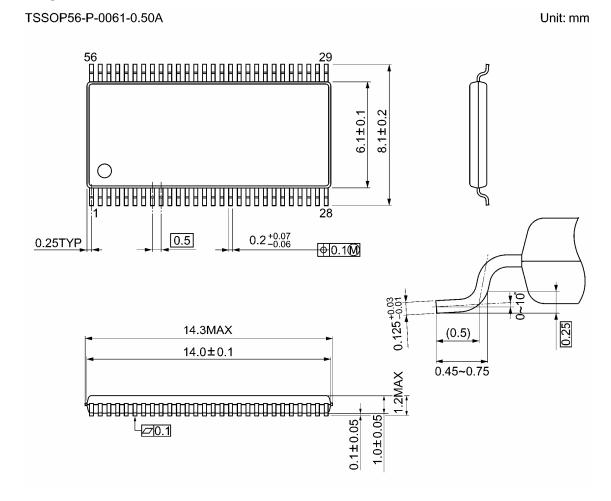


Figure 7 I/V Characteristics-Pulldown

### **Package Dimensions**



Weight: 0.25 g (typ.)

#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
   In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third parties.
- Please contact your sales representative for product-by-product details in this document regarding RoHS compatibility. Please use these products in this document in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses occurring as a result of noncompliance with applicable laws and regulations.